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34th IEEE VLSI TEST SYMPOSIUM

Caesars Palace, Las Vegas, NV, USA

April 25 - 27, 2016

Call for Papers

The IEEE VLSI Test Symposium (VTS) explores emerging trends and novel concepts in testing, debug and repair of microelectronic circuits and systems. Major topics include, but are not limited to:

- Analog/Mixed-Signal/RF Test
- ATPG & Compression
- ATE Architecture & Software
- Automotive Test & Safety
- Built-In Self-Test (BIST)
- Defect & Current Based Test
- Defect/Fault Tolerance
- Delay & Performance Test
- Design for Testability (DFT)
- Design Verification/Validation
- Embedded System & Board Test
- Embedded Test Methods
- Emerging Technologies Test
- FPGA Test
- Fault Modeling and Simulation
- Hardware Security
- Low-Power IC Test
- Microsystems/MEMS/Sensors Test
- Memory Test and Repair
- On-Line Test & Error Correction
- Power/Thermal Issues in Test
- System-on-Chip (SOC) Test
- Test Standards
- Test Economics
- Test of Biomedical Devices
- Test of High-Speed I/O
- Test Quality and Reliability
- Test Resource Partitioning
- Transients and Soft Errors
- 2.5D, 3D and SiP Test

The VTS Program Committee invites **original, unpublished Paper Submissions** for VTS 2016. Paper submissions should be complete manuscripts, up to six pages (inclusive of figures, tables, and bibliography) in a standard IEEE two-column format; papers exceeding the page limit will be returned without review. Authors should clearly explain the significance of the work, highlight novel features, and describe its current status. On the title page, please include: author name(s) and affiliation(s), and the mailing address, phone number, and e-mail address of the contact author. A 50-word abstract and five keywords identifying the topic area are also required.

Proposals for the **Innovative Practices** and **Special Sessions** tracks are also invited. The innovative practices track highlights cutting-edge challenges faced by test practitioners, and innovative solutions employed to address them. Special sessions can include invited presentations on hot topics, panels, embedded tutorials. Innovative practices and special session track proposals should include a title, name and contact information of the session organizer(s), a 150-to-200 word abstract, and a list of **prospective** participants.

All submissions are to be made electronically through the VTS website. The deadline for all submissions is **October 16th, 2015**. Detailed instructions for submissions will be found at the symposium website <http://www.tttc-vts.org>. Authors will be notified of the disposition of their papers by **December 20th, 2015**. A submission will be considered as evidence that, upon acceptance, the author(s) will submit a final camera-ready version of the paper for inclusion in the proceedings, and will present the paper at the symposium. A full registration of at least one author is required for publication. In the case of innovative practices and special sessions, the organizers commit to submitting a session title, abstract and list of participants for inclusion in the symposium proceedings.

VTS 2016 will present a **Best Paper Award**, a **Best Special Session Award**, and a **Best Innovative Practices Session Award** based on the evaluations of reviewers, attendees, and an invited panel of judges. We also plan to organize a **Student Poster Competition** and a **TTTC Best Doctoral Thesis Contest**, details for which will be available through the VTS website at a later date. The Best Paper of VTS 2015 and the Best Innovative Practices presentation will be invited to resubmit to the IEEE Design & Test of Computers where they will undergo a regular, but expedited, review process.

TTTC Test Technology Educational Program (TTEP) tutorials on emerging test technology topics will be offered in conjunction with VTS 2016. Tutorial proposals should be submitted according to TTEP 2016 submission guidelines, which will be posted on <http://computer.org/tab/tttc/teg/ttep>.

VTS 2016 is sponsored by the Test Technology Technical Council (TTTC) of the IEEE Computer Society. For more information on the symposium, please visit the VTS website at <http://www.tttc-vts.org> or contact:

For general information:

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